Morphological and Crystallographic Characterization of Nanoparticles by Granulometry Image Analysis and Rietveld Refinement Methods

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ABSTRACT: The particle size distribution of the resultant cobalt ferrite samples was determined from Scanning Electron Microscopy (SEM) images using the granulometry image analysis method. The results showed the nanosized particles of the samples. The X-Ray Diffraction (XRD) patterns of samples were also analyzed by Rietveld refinement method. The results indicated that the precipitated sample at 95 °C had cubic cobalt ferrite structure with F3dm:3 space group and high crystallinity. The lattice parameters, microstrain and crystallite size of samples were also calculated from the XRD pattern. With increasing the precipitation temperature, the crystallite and particle sizes were increased while the lattice parameter and microstrain were decreased. Regarding the results, it can be concluded that the lattice parameter of cobalt ferrite has a diverse relationship with crystallite size.

KEYWORDS: Local thresholding algorithm; X-ray diffraction; Image processing; Particle size distribution.

INTRODUCTION
The physical and chemical properties of materials are depended to the particle size especially in nanometer scale due to their large surface-to-volume ratio [1-7]. For this reason, nanomaterials have received considerable attention in recent years [8-12]. Their unique properties have presented novel applications and have been widely studied [13-15]. Nanomaterials with magnetic properties have been using in technological applications and fundamental studies [16,17]. Magnetic nanoparticles and their suspensions have been used as optical devices [18], sensors [19], magnetic resonance imaging, [20], magnetically guided drug delivery and cancer therapy [21,22]. Cobalt ferrite is one of the promising compounds, applied as magnetic materials in various
functions. It also shows strong anisotropy, high microwave magnetic loss, and moderate saturation magnetization at room temperature [23]. Various electrochemical, sol-gel, mechanical alloying, micro-emulsion, physical vapor deposition, and laser deposition methods were presented for preparation of cobalt ferrite nanoparticles and films [23-28]. But, the majorities of these methods require high treatment or post annealing temperature in order to enhance the crystallinity and magnetic properties of cobalt ferrite.

The facility of data gathering in the X-Ray Diffractometry (XRD) makes it the prominent characterization method in material science. Usually the XRD pattern was utilized for phase determination and crystallite size estimation with scherrer’s relation. However, many sophisticated methods such as Rietveld refinement can be applied for accurate determination of phase structure and structural parameters such as lattice parameter, bond length, and cell volume as well as microstructural parameters (texture, crystallite size, micro strain) [29-32].

In this work, we attempt to utilize the granulometry image analysis and the Rietveld refinement method to elaborate characterization of synthesized nanoparticles beside common techniques. Cobalt ferrite nanoparticles were prepared with appropriate crystallinity without the requirement of post annealing.

**EXPERIMENTAL**

**SECTION**

**Chemical reagents**

The 120 mL aqueous solution containing 80 mM FeCl$_3$.6H$_2$O and 40 mM Co(CH$_3$COO)$_2$.4H$_2$O was added very slowly into the 120 mL of 640 mM NaOH under stirring. The temperature of the reaction beaker maintained at about 55 °C. The solution of Fe$^{3+}$ and Co$^{2+}$ cations were added to the beaker. Afterward, the precipitates (sample A) were dried in the air [8]. This process was repeated at 95 °C for obtaining the sample B. The used salts were reagent grade materials from Merck. All solutions were prepared with deionized water.

**Characterization of samples**

Scanning Electron Microscopy (SEM) investigations were carried out using a Cambridge electron microscope, model Steroscan 360. The SEM images of samples were assessed using the granulometry image analysis method in order to determine mean particle size and its distribution. Fig. 1 shows the processes used for this purpose.

![Fig. 1: Procedure of granulometry (a) selected initial image (b) Smoothed version of a selected area on initial image (c) The binary image of smoothed image using local thresholding (d) histogram of particle diameter distribution produced by morphological techniques.](image)

In accordance with parts (a) and (b) of this figure, the erosion and dilation of the SEM image of sample B were smoothed by image histogram adjustment. In part (c) of Fig. 1, the enhanced image was converted to the binary image by a local thresholding algorithm. Eventually, the particle size distribution can be computed by applying for the morphological opening of increasing size. For each opening, the sum of all the pixel value in it was computed. This sum is well known as surface area of image [33]. The surface area of image can be plotted against radii of disk shaped opening. The surface area will be reduced between the successful openings. Regarding these statements, the negative value of surface area differential versus diameter of disc shaped opening is equal to the particle size distribution (part (d) of Fig. 1).
The microstructure and structure of samples were also determined from X-Ray Diffraction analysis (XRD, Philips X’Pert diffractometer) by Rietveld refinement method. Rietveld refinement [29] was performed using MAUD Software [30,31]. The software calibrated by Si standard sample (NBS 640) free from the effect of reduced crystallite size and lattice defects.

RESULTS AND DISCUSSION

Parts (a) and (b) of Fig. 2 depict the particle size distribution of sample A and B calculated by image analysis granulometry. It can be seen that with increasing the precipitation temperature, the particle sizes were enhanced.

Fig. 3 illustrates the recorded XRD pattern of Samples A and B. Comparing the XRD pattern broadening and counts, it can be comprehended that Sample A with lower precipitation temperature, has lower crystallinity in comparison with Sample B. Also, it is appreciated that both samples have a cubic inverse spinel structure of CoFe₂O₄ with Fd-3m:1 space group. As can be seen from Fig. 3, Sample A has a noisy XRD pattern because of the low crystallinity. Therefore, for this sample, the Rietveld refinement with reliable result could not be performed. For Sample A, the lattice parameter computed by Bragg’s law considering the main diffraction line position. The microstrain and crystallite size of same sample were calculated by Williamson-Hall plot [34] using the (311), (004), (333) and (044) lines. Fig. 4 depicts this plot for Sample A and Equation (1) shows the method of the microstrain and crystallite size determination.

\[ \beta \cos(\theta) = \frac{\lambda}{D} + 4\varepsilon \sin(\theta) \]  

In equation (1), \( \beta \) denotes the XRD lines broadening that are free from instrument broadening, \( \lambda \)= Wave length of X-ray tube (Cu kα), \( D \)=crystallite size, \( \varepsilon \)=microstrain, and \( \theta \) denotes the angle of diffraction.
Table 1: The crystallographic and microstructural parameters of as prepared samples.

<table>
<thead>
<tr>
<th>Sample</th>
<th>a (nm)</th>
<th>D (nm)</th>
<th>ε</th>
<th>R%</th>
<th>P (nm)</th>
</tr>
</thead>
<tbody>
<tr>
<td>A</td>
<td>0.843</td>
<td>37.6</td>
<td>0.005</td>
<td>----</td>
<td>98.450</td>
</tr>
<tr>
<td>B</td>
<td>0.839</td>
<td>97.59</td>
<td>0.0021</td>
<td>9.45</td>
<td>150.03</td>
</tr>
</tbody>
</table>

a = lattice parameter, D = crystallite size, ε = microstrain, R = agreement factor of refinement, P = mean value of particle size calculated from SEM images.

Fig. 5: Recorded XRD pattern (dot) and Rietveld calculated pattern of Sample B. The differences of these two patterns is also shown in the figure. The bars illustrate the position of the cobalt ferrite diffraction lines.

Rietveld refinement method, respectively. The reported results indicated that the prepared sample at 95 °C has high crystallinity with F3dm:3 space group. With increasing the temperature, crystallite and particle sizes were enhanced while the lattice parameter and microstrain were decreased. Also, the lattice parameter of cobalt ferrite has diverse relationship with crystallite size.

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